NSN 5962-00-131-2374

Digital Microcircuit - Page 1 of 1



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Between 0.750 inches and 0.784 inches Bedwy Width: Between 0.220 inches and 0.280 inches Body Width: Between 0.220 inches and 0.280 inches Body Height: 0.180 inches Operating Tempurature Range: -0.0.480.0 degrees celsius Storage Tempurature Range: -0.5.0/+150.0 degrees celsius Features Provided: Monolithic and hermetically sealed and positive outputs and medium speed Inclosure Material: Ceramic and glass Inclosure Material: Output Logic Form: Diode-transistor logic Input Circuit Pattern: Dual-in-ine Output Lircuit Pattern: Dual 5 input Design Function And Quantity: 2 gate, nand-nor Time Rating Per Chacteristic: 50.00 nanoseconds propagation delay time, low to high level output and 35.00 nanoseconds propagation delay time, high to low level output Test Data Document: 08458-94327 drawing (this is the basic governing drawing, such as a contractor drawing, original equipment manufacturer drawing, etc.; excludes any specification, standard or other document that may be referenced in a basic governing drawing) Shelf Life: Na Unit Of Measure: - Demilitarization: Yes - demil/mil	
Body Width: Between 0.220 inches and 0.280 inches Body Height: 0.180 inches Operating Tempurature Range: -20.0/+80.0 degrees celsius Storage Tempurature Range: -65.0/+150.0 degrees celsius Features Provided: Monolithic and hermetically sealed and positive outputs and medium speed Inclosure Material: Ceramic and glass Inclosure Material: Ceramic and glass Inclosure Configuration: Dual-in-line Output Logic Form: Diode-transistor logic Input Circuit Pattern: Dual 5 input Design Function And Quantity: 2 gale, nand-nor Time Rating Per Chacteristic: 50.00 nanoseconds propagation delay time, low to high level output and 35.00 nanoseconds propagation delay time, high to low level output Test Data Document: 08458-94327 drawing (this is the basic governing drawing, such as a contractor drawing, original equipment manufacturer drawing, etc.: excludes any specification, standard or other document that may be referenced in a basic governing drawing) Shelf Life: N/a Unit Of Measure: Demilitarization:	Body Length:
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Unit Of Measure: Demilitarization:	Shelf Life:
 Demilitarization:	N/a
	Unit Of Measure:
Yes - demil/mli	Demilitarization:
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